

30 A, 900 V very fast IGBT

Features

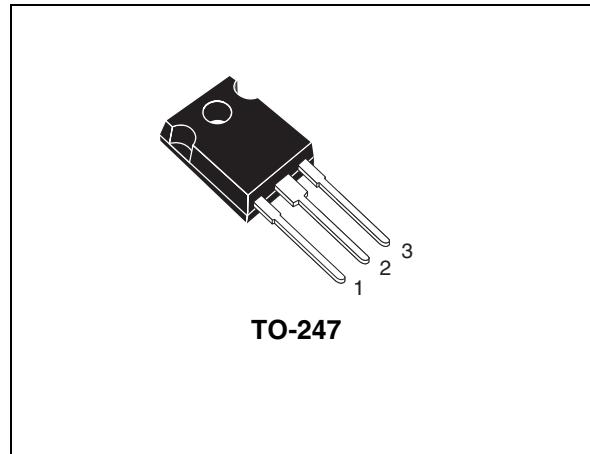
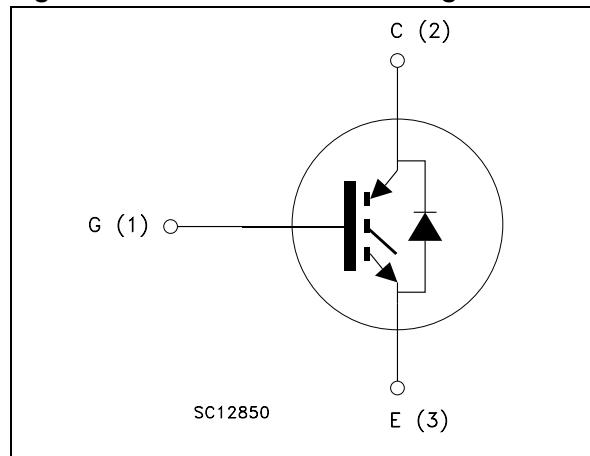
- Low on-losses
- Low on-voltage drop ($V_{CE(sat)}$)
- High current capability
- Low gate charge
- Ideal for soft switching application

Application

- Induction heating

Description

This IGBT utilizes the advanced PowerMESH™ process resulting in an excellent trade-off between switching performance and low on-state behavior.

**Figure 1. Internal schematic diagram****Table 1. Device summary**

| Order code | Marking | Package | Packaging |
|------------|----------|---------|-----------|
| STGW30N90D | GW30N90D | TO-247 | Tube |

Contents

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|------------|------------|
| V_{CES} | Collector-emitter voltage ($V_{GE} = 0$) | 900 | V |
| $I_C^{(1)}$ | Collector current (continuous) at $T_C = 25^\circ C$ | 60 | A |
| $I_C^{(1)}$ | Collector current (continuous) at $T_C = 100^\circ C$ | 30 | A |
| $I_{CL}^{(2)}$ | Turn-off latching current | 135 | A |
| $I_{CP}^{(3)}$ | Pulsed collector current | 135 | A |
| V_{GE} | Gate-emitter voltage | ± 25 | V |
| P_{TOT} | Total dissipation at $T_C = 25^\circ C$ | 220 | W |
| I_F | Diode RMS forward current at $T_C = 25^\circ C$ | 30 | A |
| I_{FSM} | Surge non repetitive forward current $t_p=10$ ms sinusoidal | 100 | A |
| T_J | Operating junction temperature | -55 to 150 | $^\circ C$ |

1. Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{j(max)} - T_C}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_C(T_C))}$$

2. $V_{clamp}=900V$, $T_J=125^\circ C$, $R_G=10 \Omega$, $V_{GE}=15 V$
3. Pulse width limited by maximum junction temperature and turn-off within RBSOA

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|--|-------|--------------|
| $R_{thj-case}$ | Thermal resistance junction-case IGBT | 0.57 | $^\circ C/W$ |
| | Thermal resistance junction-case (diode) | 1.6 | $^\circ C/W$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient | 50 | $^\circ C/W$ |

2 Electrical characteristics

($T_J = 25^\circ\text{C}$ unless otherwise specified)

Table 4. Static electrical characteristics

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|---|---|------|------------|-----------|---------------------|
| $V_{(\text{BR})\text{CES}}$ | Collector-emitter breakdown voltage ($V_{\text{GE}} = 0$) | $I_C = 1 \text{ mA}$ | 900 | | | V |
| $V_{\text{CE}(\text{sat})}$ | Collector-emitter saturation voltage | $V_{\text{GE}} = 15 \text{ V}, I_C = 20 \text{ A}$ $V_{\text{GE}} = 15 \text{ V}, I_C = 20 \text{ A}, T_J = 125^\circ\text{C}$ | | 2.2 2.0 | 2.75 | V V |
| $V_{\text{GE}(\text{th})}$ | Gate threshold voltage | $V_{\text{CE}} = V_{\text{GE}}, I_C = 250 \mu\text{A}$ | 3.75 | | 5.75 | V |
| I_{CES} | Collector-emitter cut-off current ($V_{\text{GE}} = 0$) | $V_{\text{CE}} = 600 \text{ V}$ $V_{\text{CE}} = 600 \text{ V}, T_J = 125^\circ\text{C}$ | | | 500 10 | μA mA |
| I_{GES} | Gate-emitter leakage current ($V_{\text{CE}} = 0$) | $V_{\text{GE}} = \pm 20 \text{ V}$ | | | ± 100 | nA |
| $g_{\text{fs}}^{(1)}$ | Forward transconductance | $V_{\text{CE}} = 25 \text{ V}, I_C = 20 \text{ A}$ | | 14 | | S |

1. Pulse duration: 300 μs , duty cycle 1.5%

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|------------------|------------------------------|---|------|------|------|------|
| C_{ies} | Input capacitance | | | 2510 | | pF |
| C_{oes} | Output capacitance | | - | 175 | - | pF |
| C_{res} | Reverse transfer capacitance | $V_{\text{CE}} = 25 \text{ V}, f = 1 \text{ MHz}, V_{\text{GE}} = 0$ | | 30 | | pF |
| Q_g | Total gate charge | | | 110 | | nC |
| Q_{ge} | Gate-emitter charge | | - | 16 | - | nC |
| Q_{gc} | Gate-collector charge | $V_{\text{CE}} = 900 \text{ V}, I_C = 20 \text{ A}, V_{\text{GE}} = 15 \text{ V}$ | | 49 | | nC |

Table 6. Switching on/off (inductive load)

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|--|------|-------------------|------|------------------------------|
| $t_{d(on)}$ t_r (di/dt) _{on} | Turn-on delay time Current rise time Turn-on current slope | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17) | - | 29 11 1820 | - | ns ns A/ μs |
| $t_{d(on)}$ t_r (di/dt) _{on} | Turn-on delay time Current rise time Turn-on current slope | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125 \text{ }^\circ\text{C}$ (see Figure 17) | - | 27 14 1580 | - | ns ns A/ μs |
| $t_r(V_{off})$ $t_{d(off)}$ t_f | Off voltage rise time Turn-off delay time Current fall time | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17) | - | 90 275 312 | - | ns ns ns |
| $t_r(V_{off})$ $t_{d(off)}$ t_f | Off voltage rise time Turn-off delay time Current fall time | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125 \text{ }^\circ\text{C}$ (see Figure 17) | - | 150 336 592 | - | ns ns ns |

Table 7. Switching energy (inductive load)

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|--|------|----------------------|------|---|
| $E_{on}^{(1)}$ $E_{off}^{(2)}$ E_{ts} | Turn-on switching losses Turn-off switching losses Total switching losses | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17) | - | 1660 4438 6098 | - | μJ μJ μJ |
| $E_{on}^{(1)}$ $E_{off}^{(2)}$ E_{ts} | Turn-on switching losses Turn-off switching losses Total switching losses | $V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125 \text{ }^\circ\text{C}$ (see Figure 17) | - | 3015 6900 9915 | - | μJ μJ μJ |

1. E_{on} is the turn-on losses when a typical diode is used in the test circuit in figure 2. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature ($25 \text{ }^\circ\text{C}$ and $125 \text{ }^\circ\text{C}$)
2. Turn-off losses include also the tail of the collector current

Table 8. Collector-emitter diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------------|--|--|------|-----------------|------|---------------|
| V_F | Forward on-voltage | $I_F = 20 \text{ A}$ $I_F = 20 \text{ A}$, $T_J = 125 \text{ }^\circ\text{C}$ | - | 1.9 1.7 | 2.5 | V V |
| t_{rr} Q_{rr} I_{rrm} | Reverse recovery time Reverse recovery charge Reverse recovery current | $I_F = 20 \text{ A}$, $V_R = 27 \text{ V}$, $T_J = 125 \text{ }^\circ\text{C}$, $di/dt = 100 \text{ A}/\mu\text{s}$ (see Figure 20) | - | 152 722 9 | - | ns nC A |

2.1 Electrical characteristics (curves)

Figure 2. Output characteristics

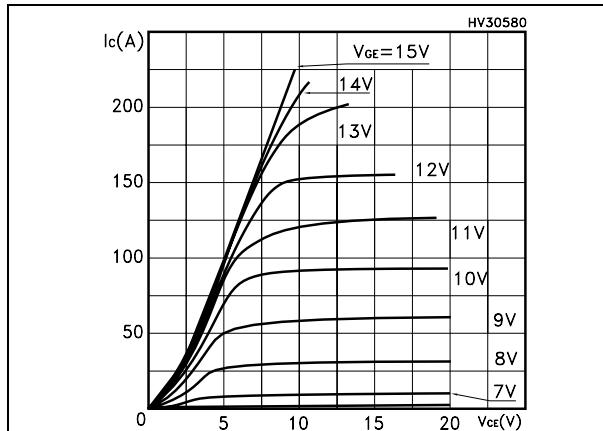


Figure 3. Transfer characteristics

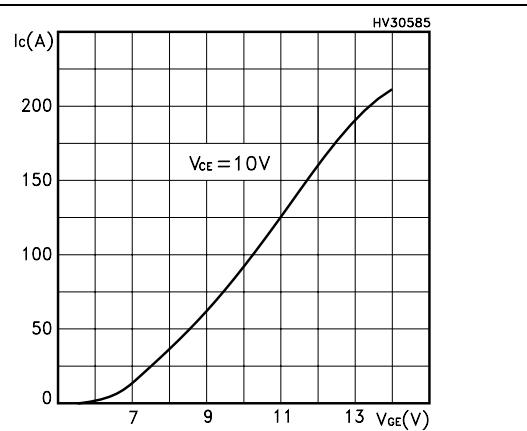


Figure 4. Transconductance

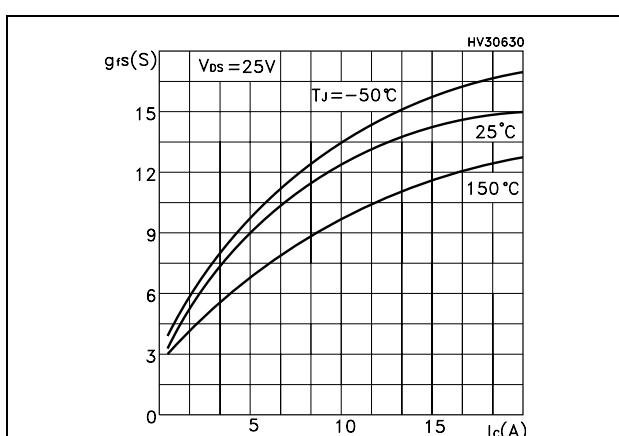


Figure 5. Collector-emitter on voltage vs. temperature

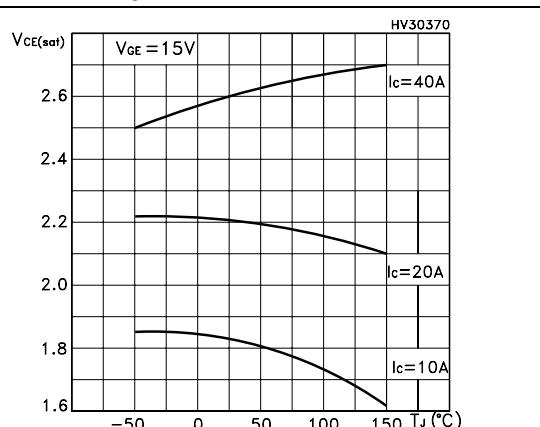


Figure 6. Gate charge vs. gate-source voltage

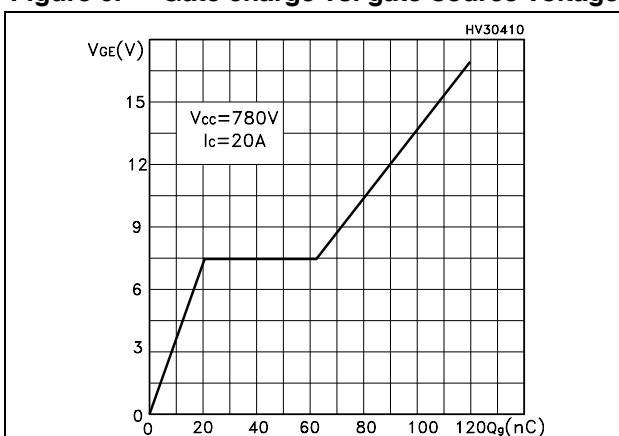


Figure 7. Capacitance variations

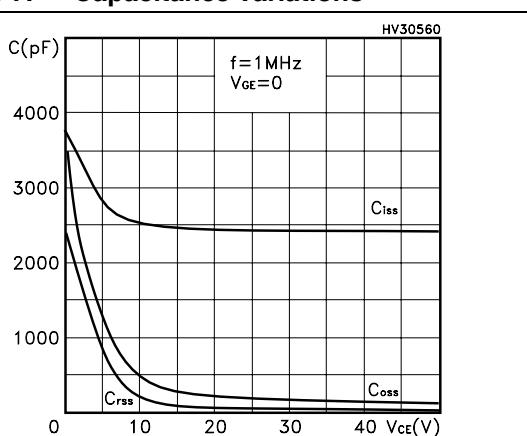


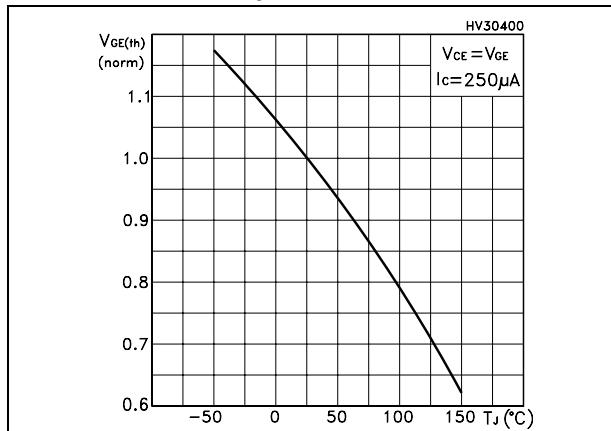
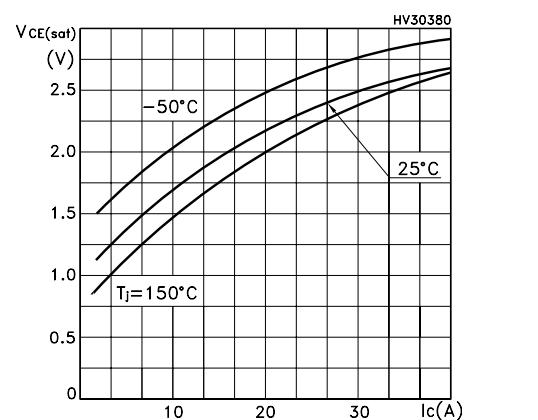
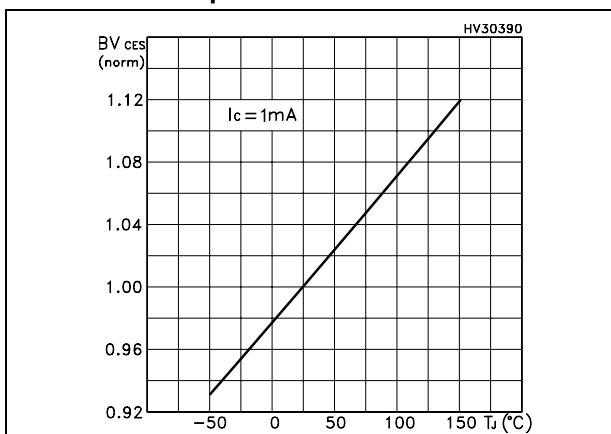
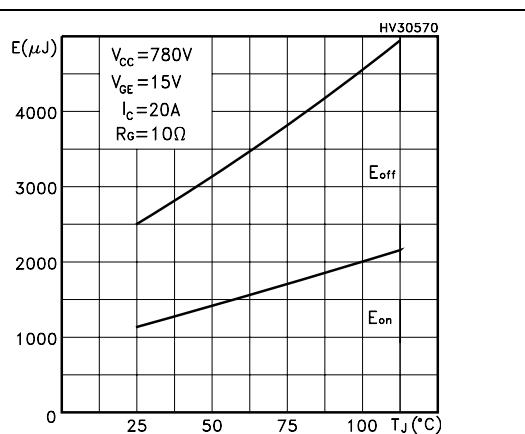
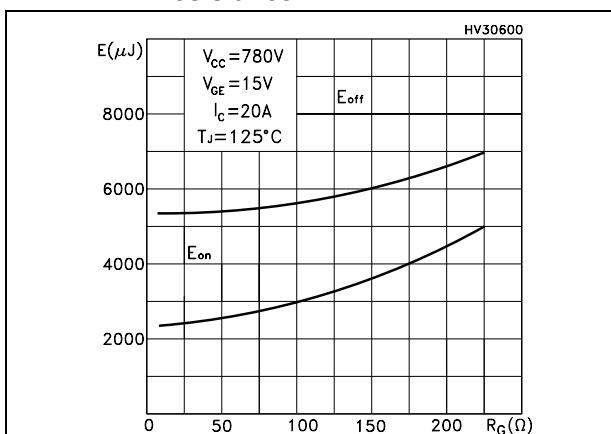
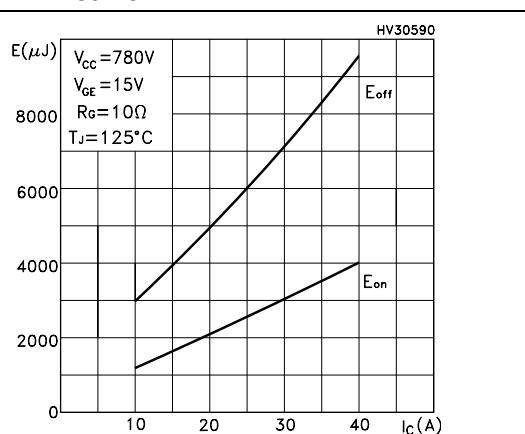
Figure 8. Normalized gate threshold voltage vs. temperature**Figure 9. Collector-emitter on voltage vs. collector current****Figure 10. Normalized breakdown voltage vs. temperature****Figure 11. Switching losses vs. temperature****Figure 12. Switching losses vs. gate resistance****Figure 13. Switching losses vs. collector current**

Figure 14. Thermal Impedance

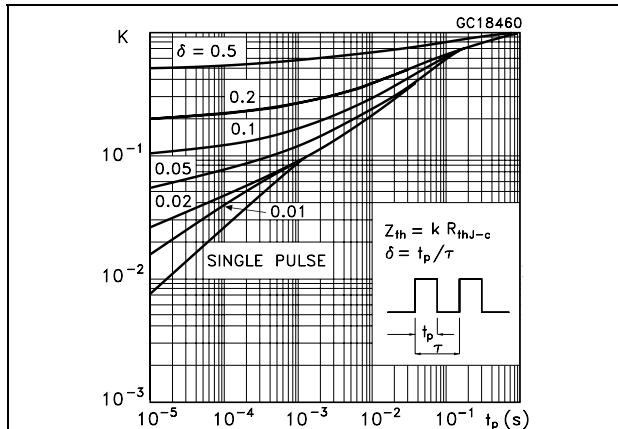


Figure 15. Reverse biased SOA

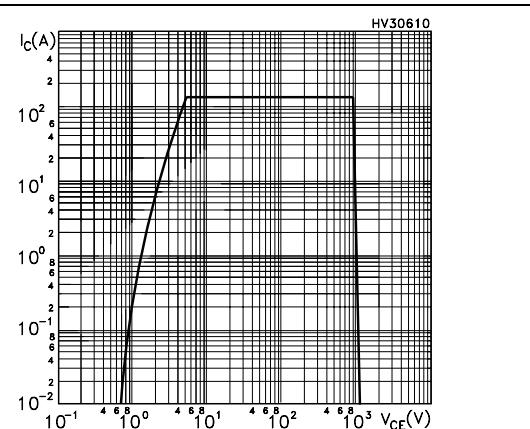
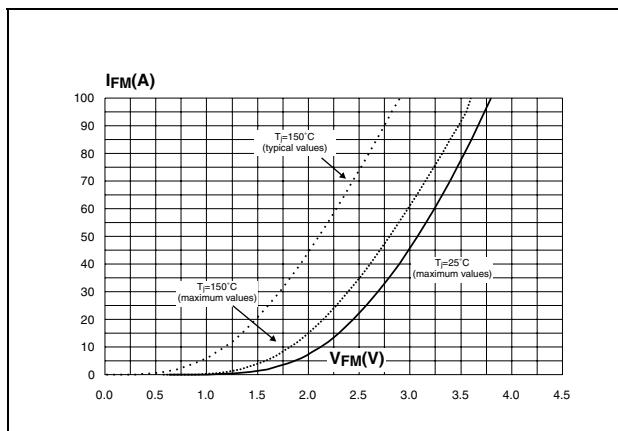


Figure 16. Forward voltage drop vs. forward current



3 Test circuit

Figure 17. Test circuit for inductive load switching

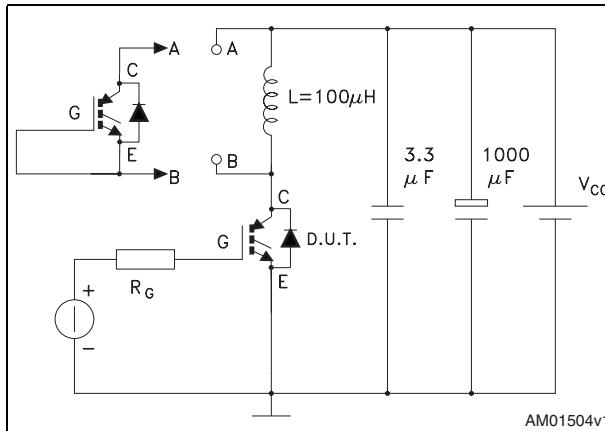


Figure 18. Gate charge test circuit

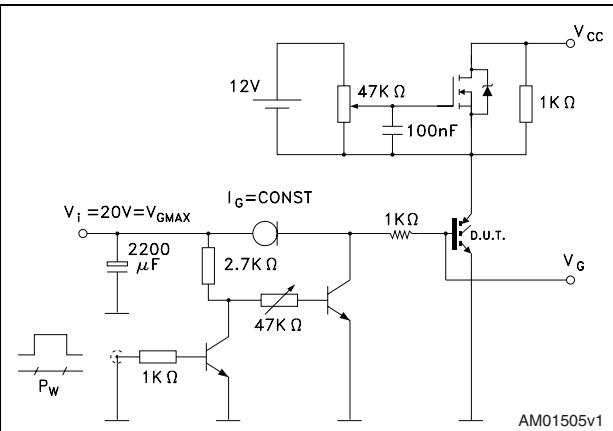


Figure 19. Switching waveform

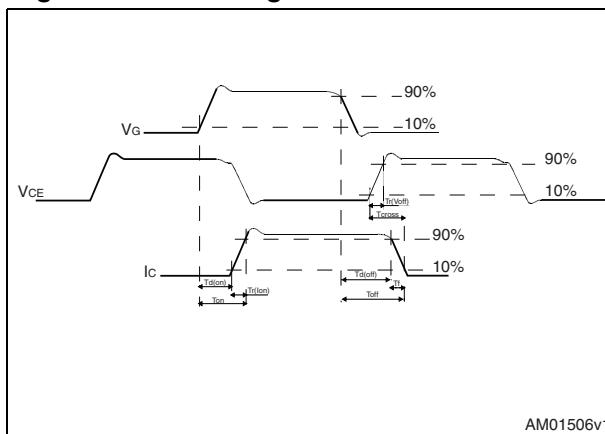
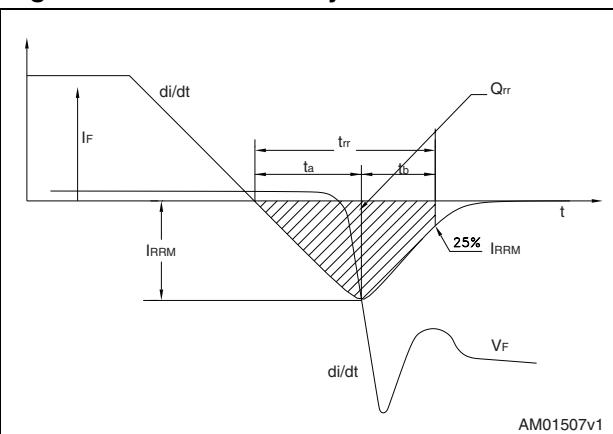


Figure 20. Diode recovery time waveform

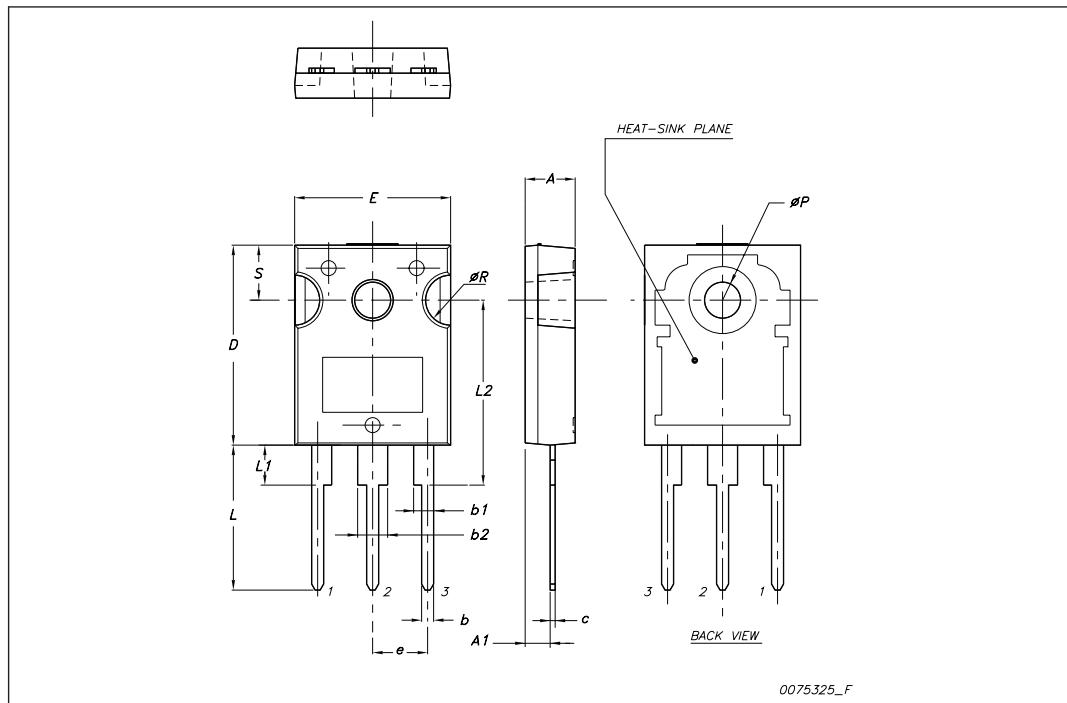


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

TO-247 mechanical data

| Dim. | mm. | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.85 | | 5.15 |
| A1 | 2.20 | | 2.60 |
| b | 1.0 | | 1.40 |
| b1 | 2.0 | | 2.40 |
| b2 | 3.0 | | 3.40 |
| c | 0.40 | | 0.80 |
| D | 19.85 | | 20.15 |
| E | 15.45 | | 15.75 |
| e | | 5.45 | |
| L | 14.20 | | 14.80 |
| L1 | 3.70 | | 4.30 |
| L2 | | 18.50 | |
| øP | 3.55 | | 3.65 |
| øR | 4.50 | | 5.50 |
| S | | 5.50 | |



5 Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 19-Jul-2006 | 1 | First issue. |
| 02-Sep-2009 | 2 | <ul style="list-style-type: none">– Document status promoted from preliminary data to datasheet– <i>Section 4: Package mechanical data</i> has been updated |

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